Comments

PZT Tube Electrodes KLZ 16/0256

PROJECT NUMBER: 12422 (HYAZINT)

CLEANROOM START: 2016.05.12

CLEANROOM END: 2016.05.26

Short description of the fabricated chips:

SUBSTRATES:

• (6+6) x Silicon, Prime Single Side Polished, 100 mm diam, 525 um thickness.

STRUCTURES:

- 2x3 Wafers: Polyimide electrodes (PI-Platinum-PI), 3 variations, 2 copies each.
- 6 Wafers: Spin coating and curing of Polyimide (5 um). To be stored.

MASK SET:

- 10 "U ELECTRODES"
 - o 0 "METAL"
 - o 1 "POLYIMIDE"
- 20 "ZIP ELECTRODES"
 - o 0 "METAL"
 - o 1 "POLYIMIDE"
- 30 "ROLL ELECTRODES"
 - o 0 "METAL"
 - o 1 "POLYIMIDE"

Process

1.	Spin-coating of polyimide	Always check vacuum is working!
	• Targeted thickness: 5 μm	Coated 12 wafers:
	• Statically dispense 2 ml of U-Varnish S	6 with minor defects, stored:
	• 3000 rpm, 30 s	Bubbles, streaks, "orange skin"
2.	Softbake:	Continued processing the best C wefers
	Hotplate for 3 min @ 120 °C	Continued processing the best 6 wafers
3.	Curing in N2 Atmosphere:	
	• Oven Program 3 : 10 min @ 450 °C	
	• (Whole temperature ramping process time:	
	approx. 3.5 hours)	

Process Comments

4.	HMDS-priming:	
	Oven approx. 15min.	
	• (Or on the HDMS hotplate (Program 1))	
5.	Spin Coating of negative resist:	
	• Statically dispense 2.0ml of Ma-N 1420	
	• 4000 rpm, 30 sec	
6.	Softbake:	
	• 100°C, 120 s	
7.	Exposure: "0 METAL"	
	Bright field mask, flat alignment, foil mask, soft	
	contact	
	Alignment gap: 130 um	
	• WEC Offset: 0	
	• 60 sec @ 9mW (i.e. > normal exp. dose).	
8.	<u>Develop</u> □	After 1m50s underetching was too
	• Ma-D 533/S: 01:45-01:55 min 2m 20s	small. Added 30 s.
	• In Petri dish (static)	
	• Rinse, spin dry	
9.	O2-flash (Improve adhesion of Platinum) □	
	• TePla (Barrel): Prog. "O2-flash" 2 min @ 80 W	
10.	DC-sputtering of Platinum	One of the u-electrodes wafer not ideal
	Leybold UNIVEX 500	Shutter was only half opened
	• Target film thickness: 100 nm	Shutter was only hall opened
	• 400 Watt – 2 x 50 sec – wait interval: > 20 min!	

11	LIET OFF Platinum (overnight):	
11.	LIFT-OFF Platinum (overnight):	
	 DMSO (coarse then fine) 	

Process Comments

- If needed, heat to 70 degC
- Rinse, spin dry

12.	2. Optical inspection					
13.	3. Measure Pt film thickness with profilometer					
14.	O2-flash (Improve adhesion of 2^{nd} polyimide layer) \square					
	• Tel	Pla (Barrel): Prog. "O2-flash" 2 min @ 80 W				
15.	Spin-co	pating of polyimide				
	• Tar	geted thickness: 5 μm				
	• Sta	tically dispense 2.5 ml of U-Varnish S				
	• No:	te: Use more PI as on a virgin Si-Wafer!				
	• 300	00 rpm, 30 s				
16.	Softbal	ke				
	• Ho	tplate for 3 min @ 120 °C				
17.	Curing	in N2 Atmosphere				
	• Ove	en Program 3: 10 min @ 450 °C				
	• (W	hole temperature ramping process time:				
	ар	prox. 3.5 hours)				

18.	HMDS-	priming				
	• Ove	en approx. 15min				
	• (Or	on the HDMS hotplate (Program 1))				
19.	Double	Spin coating of positive photoresist				
	• Tar	rgeted thickness: t ≈ 26 μm				
	• Sta	tically dispense 2.5 ml of AZ 9260				
	• 1 st	layer: 1600 rpm for 30s (t _a = 1000ms)				
	• Let wafer sit on the pins of the hotplate for 3 m					
	• Sof	tbake: hotplate 14 min @ 100°C				

 2^{nd} layer: 1600 rpm for 30s ($t_a = 1000$ ms)

Pt thickness: 90-120 um

• Lines: 55-57 um

Spacing: 42 um

Overall good looking

Process		Comments
• Let wafer sit on the pins of the hotplate for 3	3 m	
 Softbake: hotplate 14 min @ 100°C 		
20. Softbake		
 Hotplate for 3 min @ 100°C 		
21. Rehydration in wet chemistry room		
• > 3 hrs @ 60% humidity		

22. Multi-Exposure: "1 POLYIMIDE"		Always use factor x1.5 if using foil
 Bright field mask, soft exposure: 		masks!
• 5 x 15 sec @ 9mW, 50 sec wait intervals		Exposed with 5x10 sec followed by
• (If bubbles appear reduce the exposure dose	;)	flood exposure 2x3.5s, 50s wait + 0.5s
23. Development		
• Spray developer, Program L (2 times)		Residual resist thickness > 20 um
• (optional: Immersion development: AZ400K:H20		
1:3 – aprx. 3 min)		
24. RIE: "Harsh" O2-plasma etch,		Wafer in position 3 accidentally
• Recipe 09001_2: 30 mTorr, 50 sccm O ₂ :		etched twice!
• 15 min @ 120 W (Displ 200 W)		
• 20 min @ 60 W (Displ 100 W)		Added additional 5 minutes to etch through completely.
Optical inspection: Otherwise further etching!		through completely.
Testing conductivity with multimeter (if cont	act	
etching is sufficient)		
25. Resist stripping III:		
• ACE coarse, ACE fine, ISO, rinse, spin dry		
26. Profilometer :		
Measure Polyimide film thickness		
27. Optical microscope inspection:		